



INFORMATION CITED BY APPLICANTS THAT MAY BE MATERIAL TO THE  
PROSECUTION OF THE SUBJECT APPLICATION

Applicants: S. Ohkawa et al.

Attorney Docket No. SUSU121258

Application No.: 10/600,800

Group Art Unit: 2858

Filed: June 19, 2003

Title: SEMICONDUCTOR CHARACTERISTIC EVALUATION APPARATUS

OTHER INFORMATION

(Including Author, Title, Date, Pertinent Pages, Etc.)

\*Examiner Cite  
Initial No.

Dt O1 Chen, J.C., et al., "An On-Chip, Interconnect Capacitance Characterization Method With Sub-Femto-Farad Resolution," *Proceedings of the IEEE, International Conference on Microelectronic Test Structures*, Monterey, California, Vol. 10, March 1997, pp. 77-80.

Examiner

Date Considered

Donald J. Gaffin

8-10-04

\*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

JMS:snh